Electronic Supporting Information

Growth and Characterization of Zeolitic Imidazolate Framework-8

Nanocrystalline Layers on Microstructured Surfaces for Liquid Crystal Alignment

Lu-Jian Chen,*a,b Bin Luo,a Wen-Song Li,a Can Yang,a Tao Ye,b d Sen-Sen Li,a Xiao-Zhong Wang,a Yuan-Jing Cui,b,c Han-Ying Li,b,d and Guo-Dong Qianb,c

a Department of Electronic Engineering, School of Information Science and Engineering, Xiamen University, Xiamen 361005, China
b State Key Laboratory of Silicon Materials, Zhejiang University, Hangzhou, 310027, China
c Cyrus Tang Center for Sensor Materials and Applications, Department of Materials Science and Engineering, Zhejiang University, Hangzhou, 310027, China
d MOE Key Laboratory of Macromolecular Synthesis and Functionalization, Department of Polymer Science and Engineering, Zhejiang University, Hangzhou, 310027, China

E-mail: lujianchen@xmu.edu.cn

Fig. S1 Schematic of the electro-optical experimental set-up used in this work
Fig. S2 SEM top views of ZIF-8 layer prepared on pristine sol-gel films (a) after 1 cycle growth of 5 min (b), 10 min (c), and 30 min (d).

Fig. S3 SEM top views of ZIF-8 layer prepared on patterned sol-gel films with grating periods (Λ) of 3.9μm (a) after 1 cycle growth of 10 min (b), 30 min (c) and 60 min (d).